

CC2651P3 SimpleLink™ Wireless MCU Device Revision B



ABSTRACT

This document describes the known exceptions to functional specifications (advisories) to the CC2651P3 SimpleLink™ device.

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1 Advisories Matrix

Table 1-1 lists all advisories, modules affected, and the applicable silicon revisions.

Table 1-1. Advisories Matrix

MODULE	DESCRIPTION	SILICON REVISIONS AFFECTED
		B
Radio	Advisory Radio_02 — High-power PA operation at temperatures below -20°C may affect the 32-kHz crystal oscillator	Yes
Radio	Advisory Radio_04 — Reduced RX sensitivity when using integrated DC/DC converter	Yes
Power	Advisory Power_03 — Increased voltage ripple at low supply voltages when DC/DC converter is enabled	Yes
I2C	Advisory I2C_01 — I ² C module master status bit is set late	Yes
I2S	Advisory I2S_01 — I ² S bus faults are not reported	Yes
CPU	Advisory CPU_01 — Arm® Errata #838869: Store immediate overlapping exception return operation might vector to incorrect interrupt	Yes
CPU	Advisory CPU_02 — Arm® Errata #752770: Interrupted loads to SP can cause erroneous behavior	Yes
CPU, System	Advisory CPU_Sys_01 — The SysTick calibration value (register field CPU_SCS.STCR.TENMS) used to set up 10-ms periodic ticks is incorrect when the system CPU is running off divided down 48-MHz clock	Yes
System	Advisory Sys_01 — Device might boot into ROM serial bootloader when waking up from shutdown	Yes
System	Advisory Sys_05 — Elevated power-on-reset (POR) threshold voltage at low temperatures	Yes
System Controller	Advisory SYSCTRL_01 — Resets occurring in a specific 2-MHz period during initial power up are incorrectly reported	Yes
ADC	Advisory ADC_01 — Periodic ADC trigger at 200 kHz rate can be ignored when XOSC_HF is turned on or off	Yes
ADC	Advisory ADC_02 — ADC samples can be delayed by 2 or 14 clock cycles (24 MHz) when XOSC_HF is turned on or off, resulting in sample jitter	Yes
ADC	Advisory ADC_03 — Software can hang when reading the ADC FIFO if a single manual ADC trigger is generated immediately after the ADC is enabled	Yes

2 Nomenclature, Package Symbolization, and Revision Identification

2.1 Device and Development Support-Tool Nomenclature

To designate the stages in the product development cycle, Texas Instruments™ assigns prefixes to the part numbers of all devices and support tools. Each device has one of three prefixes: X, P, or null (for example, XCC2651P3). Texas Instruments recommends two of three possible prefix designators for its support tools: TMDX and TMDS. These prefixes represent evolutionary stages of product development from engineering prototypes (X/TMDX) through fully qualified production devices/tools (null/TMDS).

Device development evolutionary flow:

- X** Experimental device that is not necessarily representative of the final device's electrical specifications and may not use production assembly flow.
- P** Prototype device that is not necessarily the final silicon die and may not necessarily meet final electrical specifications.
- null** Production version of the silicon die that is fully qualified.

Support tool development evolutionary flow:

- TMDX** Development-support product that has not yet completed Texas Instruments internal qualification testing.
- TMDS** Fully-qualified development-support product.

X and P devices and TMDX development-support tools are shipped against the following disclaimer:

"Developmental product is intended for internal evaluation purposes."

Production devices and TMDS development-support tools have been characterized fully, and the quality and reliability of the device have been demonstrated fully. TI's standard warranty applies.

Predictions show that prototype devices (X or P) have a greater failure rate than the standard production devices. Texas Instruments recommends that these devices not be used in any production system because their expected end-use failure rate still is undefined. Only qualified production devices are to be used.

2.2 Devices Supported

This document supports the following device:

- [CC2651P3](#)

2.3 Package Symbolization and Revision Identification

Figure 2-1 and Table 2-1 describe package symbolization and the device revision code.

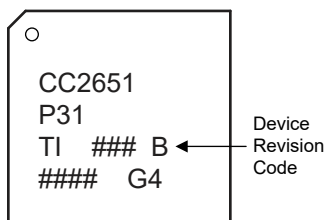


Figure 2-1. Package Symbolization

Table 2-1. Revision Identification

Device Revision Code	Silicon Revision
B	PG1.1

3 Advisories

Radio_02 ***High-Power PA Operation at Temperatures Below -20°C May Affect the 32-kHz Crystal Oscillator***

Revisions Affected: Revision B

Details: When using the high-power PA at temperatures below -20°C and high output power, the PA may affect the 32-kHz crystal oscillator due to RF load impedance mismatch. In this situation the crystal oscillator will stop, and provided the clock loss detector is enabled (OSC_DIG:CTL0.CLK_LOSS_EN = 1), the device will reset. Antenna impedances outside of VSWR of 2:1 must be avoided in all operating scenarios.

Workaround:

- For applications operating below -20°C, it is of particular importance to accurately follow the reference design for the RF balun and -matching network with respect to component values and layout. Amplitude- and phase balance through the balun must be <1dB and <6 degrees, respectively.
- For PCB designs not adhering to the TI recommended guidelines or in applications where antenna impedance is subject to change due to external factors, output power should be limited to 17 dBm maximum.
- Make sure the clock loss detector is enabled, OSC_DIG:CTL0.CLK_LOSS_EN = 1, to properly reset the device should the crystal oscillator be stopped.

Radio_04 ***Reduced RX sensitivity when using integrated DC/DC converter***

Revisions Affected: Revision B

Details: Radio RX sensitivity may be degraded by approximately 2dB when using the integrated DC/DC converter.

Workaround: Use the internal Global LDO to supply VDDR. This will result in increased current consumption as specified in the device datasheet. When using the integrated DC/DC converter, refer to the [CC13xx/CC26xx Hardware Configuration and PCB Design Considerations](#) Application Report for more information regarding layout considerations for optimum RF performance. Please refer to [CC13x1x3](#), [CC26x1x3 SimpleLink™ Wireless MCU Technical Reference Manual](#) for more information regarding power management capabilities.

Power_03 ***Increased voltage ripple at low supply voltages when DC/DC converter is enabled***

Revisions Affected: Revision B

Details: At supply voltages <2.0V, a hardware control module disables the DC/DC converter to maximize system efficiency. This module does not have enough hysteresis, causing approx 10 mV of ripple on the VDDR regulated power supply. Based on internal testing of the device, it is not anticipated that this erratum affects RF performance. However, these test results cannot ensure that a customer's application or end equipment will not be affected.

Workaround: Use the TI-provided Power driver (PowerCC26X2.c) which automatically disables the DC/DC converter when supply voltage is <2.2V.

The workaround is available in all SDK versions.

I2C_01 *I²C module master status bit is set late*

Revisions Affected: Revision B

Details: The I2C.MSTAT[0] bit is not set immediately after writing to the I2C.MCTRL register. This can lead an I²C master to believe it is no longer busy and continuing to write data.

Workaround: Add four NOPs between writing to the MCTRL register and polling the MSTAT register.
The workaround is implemented in the TI-provided I2C Master driver (I2CCC26XX.c) and in the I2C driver Library APIs (driverlib/i2c.c).
The workaround is available in all Software Development Kit (SDK) versions.

I2S_01 *I²S bus faults are not reported*

Revisions Affected: Revision B

Details: The I²S module will not set the bus error interrupt flag (I2S0.IRQFLAGS.BUS_ERR) if an I²S read or write causes a system bus fault that results from access to illegal addresses (usage error).

Workaround: Software must ensure that memory area used by the I²S DMA is accessible, meaning that the memory is powered on and the system bus is connected..
As an example; The TI-provided SPI driver SPIC26X2DMA.c will ensure that the flash memory is kept accessible also in Idle power mode if the transmit buffer address starts with 0x0 to ensure no bus faults occur. A similar approach needs to be taken if writing a peripheral driver utilizing I2S.

CPU_01 ***Arm® Errata #838869: Store immediate overlapping exception return operation might vector to incorrect interrupt***

Revisions Affected: Revision B

Details: **Configurations Affected:**

This erratum only affects systems where writeable memory locations can exhibit more than one wait state (system SRAM does not have wait states).

The Arm® Cortex®-M4 processor includes a write buffer that permits execution to continue while a store is waiting on the bus. Under specific timing conditions, during an exception return while this buffer is still in use by a store instruction, a late change in selection of the next interrupt to be taken might result in a mismatch between the interrupt acknowledged by the interrupt controller and the vector fetched by the processor.

Conditions:

- The handler for interrupt A is being executed.
- Interrupt B, of the same or lower priority than interrupt A, is pending.
- A store with immediate offset instruction is executed to a bufferable location:

```
STR/STRH/STRB <Rt>, [<Rn>,#imm]
STR/STRH/STRB <Rt>, [<Rn>,#imm]!
STR/STRH/STRB <Rt>, [<Rn>,#imm]
```

- Any number of additional data-processing instructions can be executed.
- A BX instruction is executed that causes an exception return.
- The store data has wait states applied to it such that the data is accepted at least two cycles after the BX is executed.
 - Minimally this is two cycles if the store and the BX instruction have no additional instructions between them.
 - The number of wait states required to observe this erratum needs to be increased by the number of cycles between the store and the interrupt service routine exit instruction.
- Before the bus accepts the buffered store data, another interrupt C is asserted which has the same or lower priority as A, but a greater priority than B.

Implications:

The processor should execute interrupt handler C, and on completion of handler C the processor should execute the handler for B. If the previously listed conditions are met, then this erratum results in the processor erroneously clearing the pending state of interrupt C, and then twice executing the handler for B. The first time the handler for B is executed it will be at the priority level for interrupt C. If interrupt C is pending by a level-based interrupt that is cleared by C's handler then interrupt C will be pending again after the handler for B has completed and the handler for C will be executed. If interrupt C is level based, then this interrupt will eventually become re-pending and subsequently be handled. If interrupt C is a single pulse interrupt, there is a possibility that this interrupt will be lost.

CPU_01 (continued) **Arm® Errata #838869: Store immediate overlapping exception return operation might vector to incorrect interrupt**

This bug is triggered in a rare condition. In cases where STORE experiences more than 2 wait cycles, workarounds must be used by the software developer.

- This erratum does not apply for TI-RTOS interrupts, which ensures that no *store with immediate offset* occurs within the last 5 instructions of the interrupt routine. See the following files included in all SDKs for further implementation details:
 - kernel/tirtos/packages/ti/sysbios/family/arm/m3/Hwi_asm*.sv7M
- Zero-latency interrupts in TI-RTOS (bypassing the kernel) and the no-RTOS examples in the SDK are affected by this erratum.

Workarounds:

Recommended workaround:

Ensure a DSB instruction occurs between the store and the BX instruction. For exception handlers written in C, this can be achieved by inserting the appropriate set of intrinsics or inline assembly just before the end of the interrupt function, for example:

ARMCC:

...

```
__schedule_barrier(); __asm{DSB}; __schedule_barrier(); }
```

GCC:

...

```
__asm volatile ("dsb 0xf" ::: "memory"); }
```

Note

The workaround for this bug will **not** be added automatically by the compiler.

Alternate workaround:

Disable CPU write buffering (register CPU_SCS.ACTLR.DISDEFWBUF) at the cost of significantly reduced execution speed.

CPU_02 **Arm® Errata #752770: Interrupted loads to SP can cause erroneous behavior**

Revisions Affected: Revision B

Details: An interrupt occurring during the data-phase of a single word load to the stack-pointer (SP/R13) can cause an erroneous behavior of the device. In all cases, returning from the interrupt will result in the load instruction being executed an additional time. For all instructions performing an update to the base register, the base register will be erroneously updated on each execution, resulting in the stack-pointer being loaded from an incorrect memory location.

The affected instructions that can result in the load transaction being repeated are:

- LDR SP,[Rn],#imm
- LDR SP,[Rn,#imm]!
- LDR SP,[Rn,#imm]
- LDR SP,[Rn]
- LDR SP,[Rn,Rm]

The affected instructions that can result in the stack-pointer being loaded from an incorrect memory address are:

- LDR SP,[Rn],#imm
- LDR SP,[Rn,#imm]!

Conditions:

- An LDR is executed, with SP/R13 as the destination.
- The address for the LDR is successfully issued to the memory system.
- An interrupt is taken before the data has been returned and written to the stack-pointer.

Implications:

Unless the load is being performed to device memory or strongly-ordered memory, there should be no implications from the repetition of the load.

- In the unlikely event that the load is being performed to device memory or strongly-ordered memory, the repeated read can result in the final stack-pointer value being different than had only a single load been performed.
- Interruption of the two write-back forms of the instruction can result in both the base register value and the final stack-pointer value being incorrect. This can result in apparent stack corruption and subsequent unintended modification of memory.

Workaround: Most compilers ensure this bug is not triggered by not emitting the affected instruction sequence and not using the instructions in the compiler runtime libraries. This includes:

- IAR from v6.21
- All versions of TI's Arm compiler (CCS)

A workaround for both issues can be implemented by replacing the direct load to the stack-pointer, with an intermediate load to a general-purpose register followed by a move to the stack-pointer.

If repeated reads are acceptable, then the base register update issue may be worked around by performing the stack-pointer load without the base increment followed by a subsequent ADD or SUB instruction to perform the appropriate update to the base register.

CPU_Sys_01 *The SysTick calibration value (register field CPU_SCS.STCR.TENMS) used to set up 10-ms periodic ticks is incorrect when the system CPU is running off divided down 48-MHz clock*

Revisions Affected: Revision B

Details: When using the Arm® Cortex® SysTick timer, the TENMS register field (CPU_SCS.STCR.TENMS) will always shows the value corresponding to a 48-MHz CPU clock, regardless of the CPU division factor.

Workarounds: One of the following two workarounds must be implemented:

Workaround 1: Do not use a divided down system CPU clock. In general, power savings are maximized by completing a task at full clock speed and then stopping the system CPU entirely after the task is complete.

Workaround 2: Read the system CPU division factor from the PRCM.CPUCLKDIV.RATIO register and compensate the TENMS field in software based on this value.

TI-provided drivers do not offer any functionality to divide the system CPU clock.

Sys_01 ***Device might boot into ROM serial bootloader when waking up from shutdown***

Revisions Affected: Revision B**Details:** For the conditions given below, the device will boot into and execute the ROM serial bootloader when waking up from Shutdown power mode. Intended behavior is to execute the application image. The prerequisites for this erratum to happen are:

- The wake up from Shutdown must be caused by toggling or noise on the JTAG TCK pin and not by a GPIO event.
- The Customer Configuration Section (CCFG) must have configured the bootloader with the following field values:
 - BOOTLOADER_ENABLE = 0xC5 (Bootloader enabled)
 - BL_ENABLE = 0xC5 (Bootloader pin backdoor enabled)
 - BL_PIN_NUMBER = n (any valid DIO number)

With the above prerequisites, the bootloader will be entered in the following cases:

- The CCFG bootloader pin level (BL_LEVEL) is set to 0x0 (active low) AND the input buffer enable for the DIO defined in BL_PIN_NUMBER is disabled in register IOC.IOCFGn.IE. If the input buffer is not enabled, the DIO level will always read 0 and bootloader will be entered.
- The input buffer controlled by IOC.IOCFGn.IE is enabled and the DIO input value is the same level as the CCFG bootloader pin level (BL_LEVEL) when entering Shutdown (GPIO input values are latched when entering Shutdown)

Please refer to the ICeMelter chapter in the [CC13x1x3, CC26x1x3 SimpleLink™ Wireless MCU Technical Reference Manual](#) for details on how noise entering the JTAG TCK pin can wake up the device

Workarounds: One of the following workarounds must be implemented:

- If input buffer is not enabled, use only active high bootloader pin level (BL_LEVEL)
- If input buffer is enabled, ensure DIO input pin level is not the same as bootloader pin level (BL_LEVEL) when entering Shutdown.

Sys_05 *Elevated power-on-reset (POR) threshold voltage at low temperatures*

Revisions Affected Revision B

Details When powering up the device from 0V at temperatures < 0°C, the power-on-reset (POR) circuit may not release reset until VDDS reaches 2.3V, and not at 1.8V as intended. After POR has released the reset, an affected device will continue to operate at voltages down to 1.8V.

This behavior is only observed during power up and does not occur when the device is subjected to an external pin reset, wake-up from shutdown, or watchdog reset.

The occurrence is rare and is only observed on very few devices.

Workaround **Workaround 1:** Power-up the devices at VDDS > 2.3V when operating at temperatures below 0°C.

or

Workaround 2: Power-up the device at VDDS < 2.3V, trigger the Reset-pin from a host MCU or external circuitry.

In addition, when operating the device in external regulator mode, workaround 2 must be implemented. Please note that VDDS must not exceed 1.95V in external regulator mode. *This is applicable only to devices that have external regulator mode support.*

SYCTRL_01 *Resets occurring in a specific 2-MHz period during initial power up are incorrectly reported*

Revisions Affected: Revision B

Details: If a reset occurs in a specific 2-MHz period during initial power-up (boot), the reset source in AON_PMCTL.RESETCTL.RESET_SRC is reported as PWR_ON regardless of the reset source. This means that there is a window of 0.5 μs during boot where a reset can be incorrectly reported.

Workaround: None

IOC_01 *Limited number of DIOs available for the bootloader backdoor*

Revisions Affected: Revision B

Details: The highest possible DIO number that can be used for the bootloader backdoor is limited to the number of available GPIOs minus 1. The bootloader backdoor pin is configured through SET_CCFG_BL_CONFIG_BL_PIN_NUMBER in ccfg.c. That means that if the device has x GPIOs, the highest DIO number that can be selected for the bootloader backdoor is DIO_{x-1}, even if higher DIO numbers are available for the device.

Workarounds: There are no workaround for this issue.

ADC_01 ***Periodic ADC trigger at 200 kHz rate can be ignored when XOSC_HF is turned on or off***

Revisions Affected: Revision B

Details: There is no dedicated clock source selection for the ADC clock. The clock is derived from either XOSC_HF or RCOSC_HF, but defaults to XOSC_HF-derived clock whenever this is turned on.

When the ADC clock source is switched from RCOSC_HF to XOSC_HF-derived clock, the clock will stop for 2 cycles (24 MHz).

When the ADC clock source is switched from XOSC_HF-derived clock to RCOSC_HF-derived clock, the clock will stop for additionally 12 clock cycles, as the RCOSC_HF-derived clock is not ready when switch is done.

The fact that the clock is stopped, together with the difference in frequency between XOSC_HF and RCOSC_HF, may cause the ADC sampling and conversion to finish too late to catch the next trigger.

Workaround 1: Use asynchronous sampling.

The sampling period after the issue occurs can be reduced by up to 20% (12 + 1 clock cycles at 24 MHz)

To use the ADC in asynchronous mode, by using the ADCBuf driver:

```

ADCBuf_Params params;
ADCBufCC26X2_ParamsExtension paramsExtension;

ADCBuf_Params_init(&params);
ADCBufCC26X2_ParamsExtension_init(&paramsExtension);

paramsExtension.samplingMode = ADCBufCC26X2_SAMPING_MODE_ASYNCHRONOUS;
params.custom = &paramsExtension;

```

To use the ADC in asynchronous mode, by using DriverLib API:

Call `AUXADCEnableAsync()` to enable the ADC, instead of `AUXADCEnableSync()`

Example:

```
AUXADCEnableAsync(AUXADC_REF_FIXED, AUXADC_TRIGGER_GPT0A);
```

Please note the difference between the asynchronous and synchronous ADC modes:

- In asynchronous mode, the ADC trigger ends the sampling period (which started immediately after the previous conversion), and starts conversion.
- In synchronous mode, the ADC trigger starts the sampling period (with configurable duration), followed by conversion.

Workaround 2: Ensure that XOSC_HF is not turned on or off while the ADC is used.

Workaround 3: Increase the sampling period by (12+1)/24 μs or more.

ADC_02 ***ADC samples can be delayed by 2 or 14 clock cycles (24 MHz) when XOSC_HF is turned on or off, resulting in sample jitter***

Revisions Affected: Revision B

Details: There is no dedicated clock source selection for the ADC clock. The clock is derived from either XOSC_HF or RCOSC_HF, but defaults to XOSC_HF-derived clock whenever this is turned on.

ADC_02 (continued) **ADC samples can be delayed by 2 or 14 clock cycles (24 MHz) when XOSC_HF is turned on or off, resulting in sample jitter**

When the ADC clock source is switched from RCOSC_HF to XOSC_HF-derived clock, the clock will stop for 2 cycles (24 MHz).

When the ADC clock source is switched from XOSC_HF-derived clock to RCOSC_HF-derived clock, the clock will stop for additionally 12 clock cycles, as the RCOSC_HF-derived clock is not ready when switch is done.

SCLK_HF switches from RCOSC_HF to XOSC_HF at different times compared to ADC clock. This leads to sample jitter.

Workaround 1: Use asynchronous sampling

- This will reduce the delay of 14 clock cycles down to 2 clock cycles.
- Using asynchronous sampling and an external trigger source (GPIO input pin) will eliminate the delay completely

To use the ADC in asynchronous mode by using the ADCBuf driver:

```
ADCBuf_Params params;
ADCBufCC26X2_ParamsExtension paramsExtension;

ADCBuf_Params_init(&params);
ADCBufCC26X2_ParamsExtension_init(&paramsExtension);

paramsExtension.samplingMode = ADCBufCC26X2_SAMPING_MODE_ASYNCHRONOUS;
params.custom = &paramsExtension;
```

To use the ADC in asynchronous mode by using DriverLib API:

Call `AUXADCEnableAsync()` to enable the ADC, instead of `AUXADCEnableSync()`

Example:

```
AUXADCEnableAsync(AUXADC_REF_FIXED, AUXADC_TRIGGER_GPT0A);
```

Please note the difference between the asynchronous and synchronous ADC modes:

- In asynchronous mode, the ADC trigger ends the sampling period (which started immediately after the previous conversion), and starts conversion.
- In synchronous mode, the ADC trigger starts the sampling period (with configurable duration), followed by conversion

Workaround 2: Ensure that XOSC_HF is not turned on or off while the ADC is used.

ADC_03 ***Software can hang when reading the ADC FIFO if a single manual ADC trigger is generated immediately after the ADC is enabled***

Revisions Affected: Revision B

Details: There is no dedicated clock source selection for the ADC clock. The clock is derived from either XOSC_HF or RCOSC_HF, but defaults to XOSC_HF-derived clock whenever this is turned on.

When the ADC clock source is switched from RCOSC_HF to XOSC_HF-derived clock, the clock will stop for 2 cycles (24 MHz).

When the ADC clock source is switched from XOSC_HF-derived clock to RCOSC_HF-derived clock, the clock will stop for additionally 12 clock cycles, as the RCOSC_HF-derived clock is not ready when switch is done.

The additional 12 clock cycles introduces a race between trigger-event and ADC trigger-detector to get out of reset.

Workaround 1: TI software adds a short delay at the end of the function that enables the ADC. Use SimpleLink CC13xx and CC26xx SDK 5.40 or later

Workaround 2: Ensure that XOSC_HF is not turned on or off while the ADC is used.

4 Revision History

NOTE: Page numbers for previous revisions may differ from page numbers in the current version.

DATE	REVISION	NOTES
March 2022	*	Initial Release

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